

Title (en)

TESTOR FOR MICROPROCESSOR-BASED SYSTEMS.

Title (de)

TESTGERÄT FÜR AUF MIKRORECHNER BASIERTE SYSTEME.

Title (fr)

APPAREIL D'ESSAI POUR SYSTEMES A BASE DE MICROPROCESSEURS.

Publication

EP 0032895 A4 19820322 (EN)

Application

EP 79901509 A 19810224

Priority

US 7900550 W 19790727

Abstract (en)

[origin: WO8100475A1] An automatic test apparatus (10) coupled to a bi-directional internal data and control bus (26) of a programmed microprocessor-based system (14) tests the performance of the system (14) in real time. Signal responses of the bus (26) within a known good system (12) are compared in real time to signal responses on the bus (26) of the unknown system under test (14) in order to identify faults. Faults are isolated by a sequential algorithm which stops operation at the designated occurrence of a fault, typically the first fault, and thereupon traces the error causing the fault to the subsystem or components in the system under test (14) supplying the indicated error signal to the bi-directional bus (26).

IPC 1-7

G06F 11/00; **G01R 31/28**

IPC 8 full level

G06F 11/22 (2006.01); **G06F 11/277** (2006.01)

CPC (source: EP)

G06F 11/277 (2013.01)

Citation (search report)

- US 3898621 A 19750805 - ZELINSKI PAUL A, et al
- US 3908099 A 19750923 - BORBAS ROBERT A, et al
- US 4125763 A 19781114 - DRABING RICHARD B, et al

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